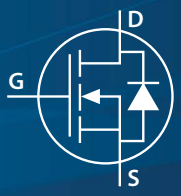
EPC2212 - Automotive 100 V (D-S) Enhancement Mode Power Transistor

V_{DS}, 100 V
$R_{DS(on)}$, 13.5 mΩ
I_D, 18 A
AEC-Q101



EFFICIENT POWER CONVERSION

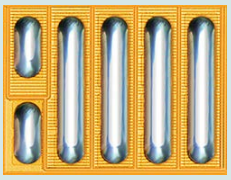
RoHS Halogen-Free

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR}. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings			
PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
I_D	Continuous (T_A = 25°C)	18	A
	Pulsed (25°C, T_{PULSE} = 300 µs)	75	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	°C
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	4	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	69	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.
See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.



EPC2212 eGaN® FETs are supplied only in passivated die form with solder bars.
Die size: 2.1 x 1.6 mm

Applications

- LiDAR/Pulsed Power Applications
- High Power Density DC-DC Converters
- Class-D Audio
- High Intensity Headlamps

Benefits

- Ultra High Efficiency
- Ultra Low $R_{DS(on)}$
- Ultra Low Q_G
- Ultra Small Footprint

www.epc-co.com/epc/Products/eGaNFETs/EPC2212.aspx

Static Characteristics (T_J = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	V_{GS} = 0 V, I_D = 250 µA	100			V
I_{DSS}	Drain-Source Leakage	V_{DS} = 100 V, V_{GS} = 0 V		10	250	µA
I_{GSS}	Gate-to-Source Forward Leakage	V_{GS} = 6 V, T_J = 25°C		0.005	1.8	mA
	Gate-to-Source Forward Leakage#	V_{GS} = 6 V, T_J = 125°C		0.015	3	mA
	Gate-to-Source Reverse Leakage	V_{GS} = -4 V		10	250	µA
$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 3 mA	0.7	1	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	V_{GS} = 5 V, I_D = 11 A		10	13.5	mΩ
V_{SD}	Source-Drain Forward Voltage	I_S = 0.5 A, V_{GS} = 0 V		1.5		V

All measurements were done with substrate connected to source.
Defined by design. Not subject to production test.

Dynamic Characteristics (T_J = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance#	V_{DS} = 50 V, V_{GS} = 0 V		339	407	pF
C_{RSS}	Reverse Transfer Capacitance			3		
C_{OSS}	Output Capacitance#			238	357	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	V_{DS} = 0 to 50 V, V_{GS} = 0 V		292		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			359		
R_G	Gate Resistance			0.4		Ω
Q_G	Total Gate Charge#	V_{DS} = 50 V, V_{GS} = 5 V, I_D = 11 A		3.2	4	nC
Q_{GS}	Gate-to-Source Charge	V_{DS} = 50 V, I_D = 11 A		0.9		
Q_{GD}	Gate-to-Drain Charge			0.6		
$Q_{G(TH)}$	Gate Charge at Threshold			0.55		
Q_{OSS}	Output Charge#	V_{DS} = 50 V, V_{GS} = 0 V		18	27	
Q_{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.
Defined by design. Not subject to production test.
Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.
Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C

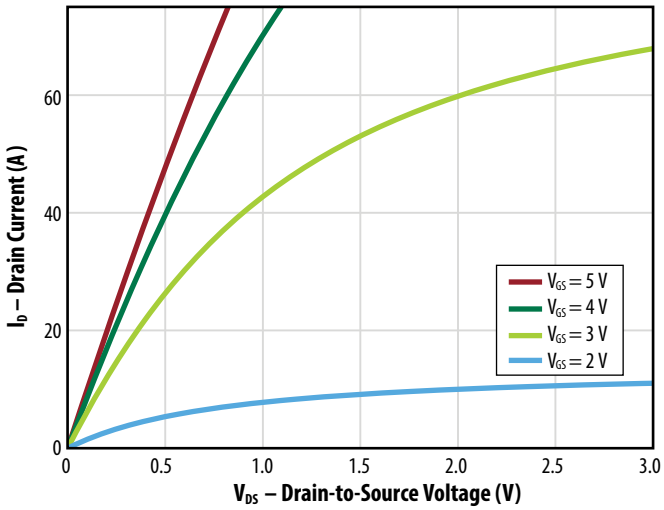


Figure 2: Transfer Characteristics

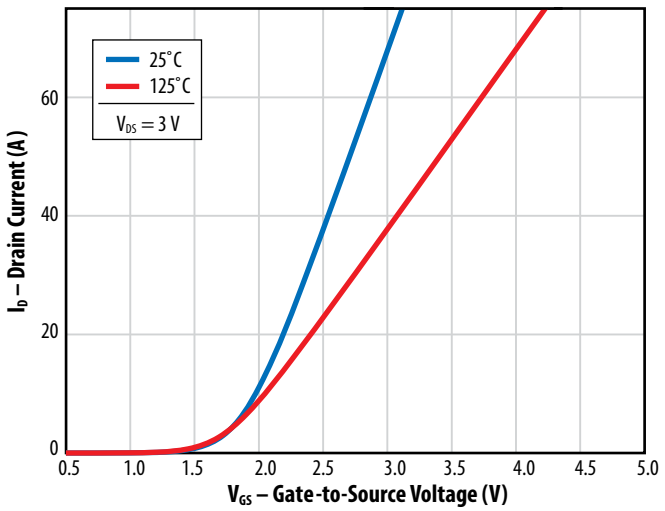


Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents

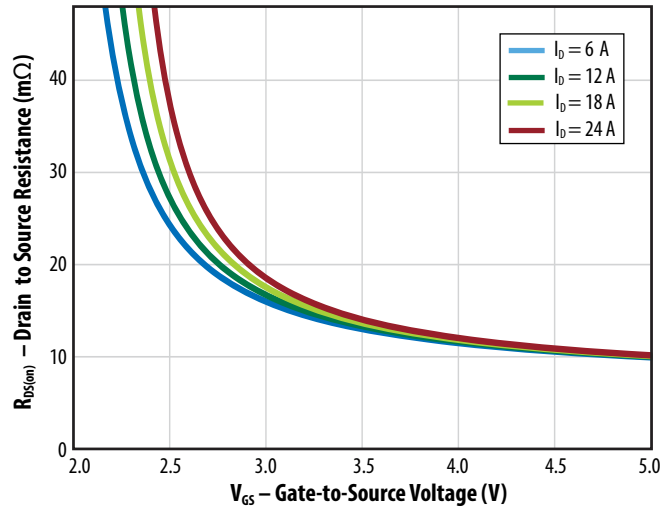


Figure 4: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

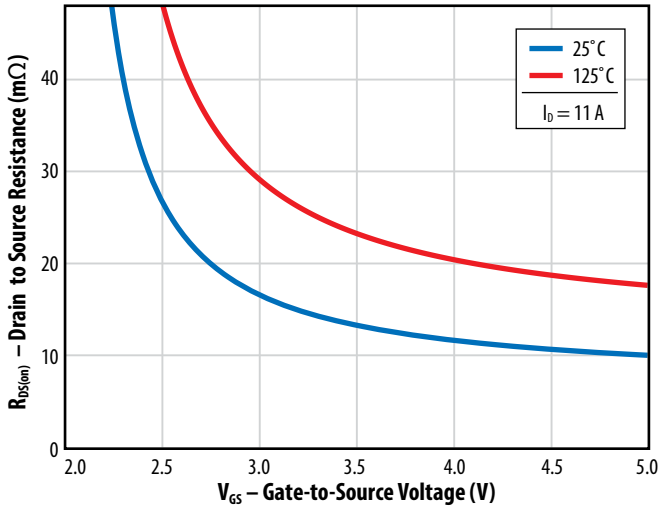


Figure 5a: Capacitance (Linear Scale)

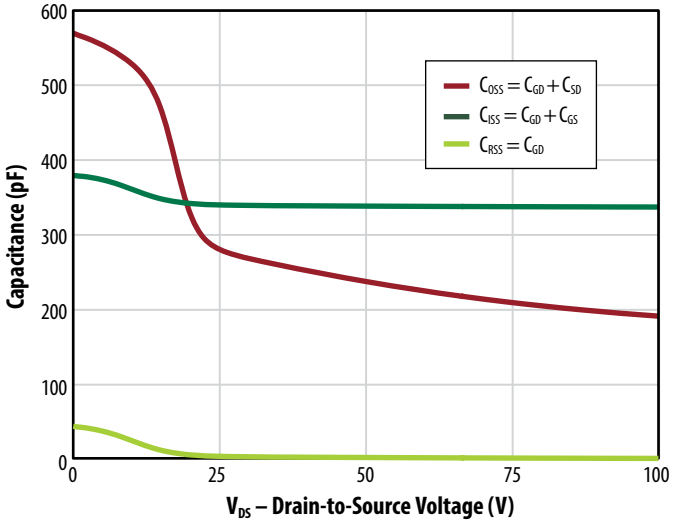


Figure 5b: Capacitance (Log Scale)

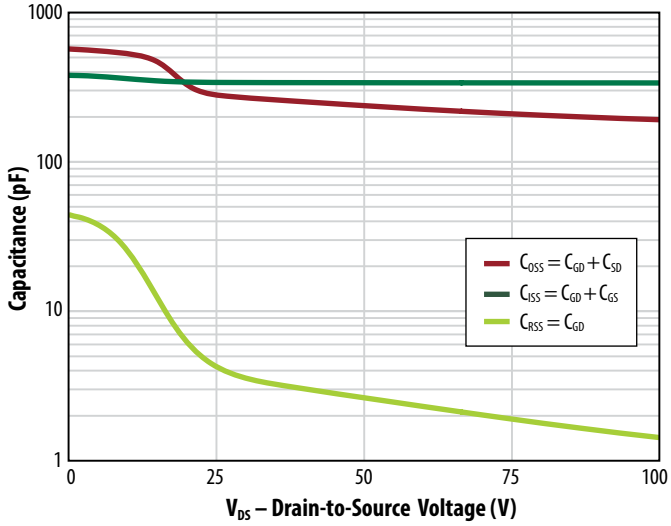


Figure 6: Output Charge and C_{OSS} Stored Energy

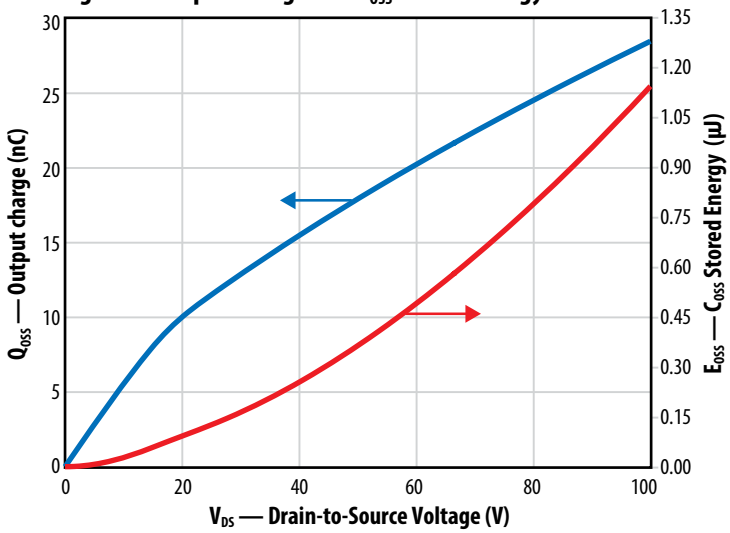


Figure 7: Gate Charge

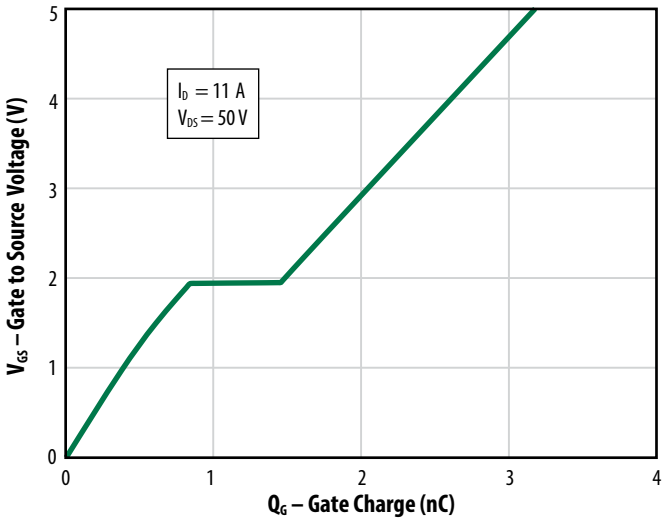


Figure 8: Reverse Drain-Source Characteristics

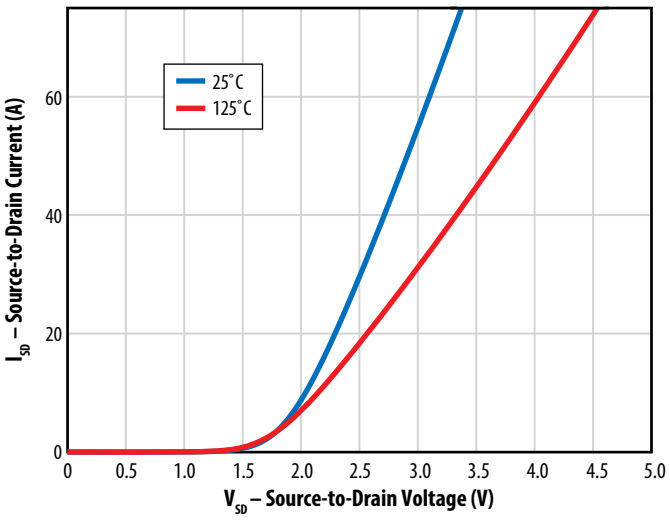


Figure 9: Normalized On-State Resistance vs. Temperature

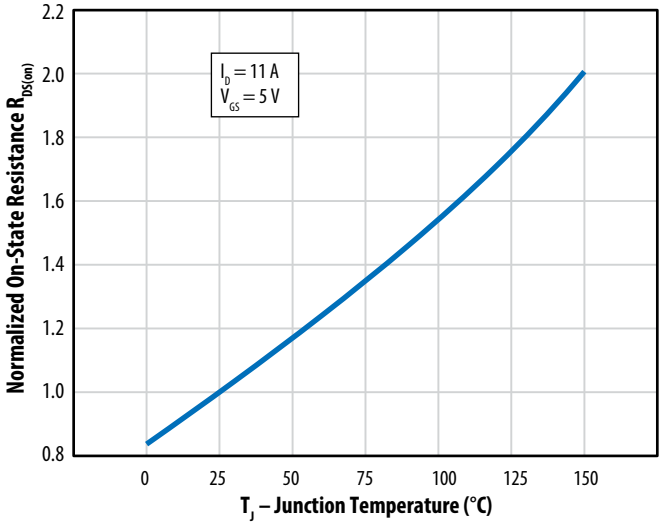


Figure 10: Normalized Threshold Voltage vs. Temperature

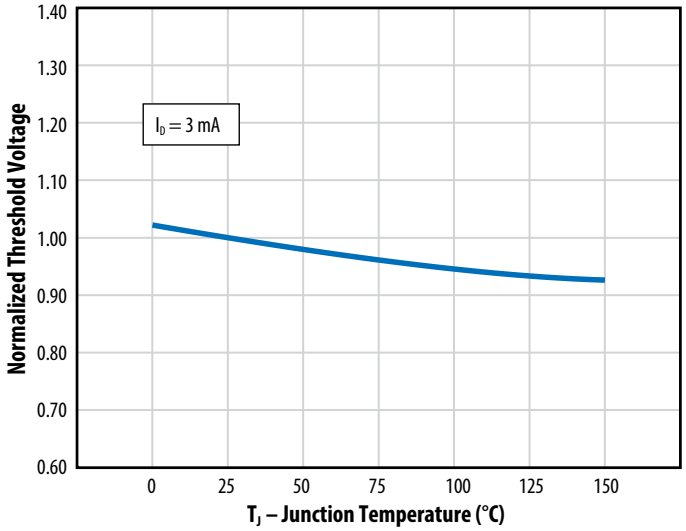


Figure 11: Transient Thermal Response Curves

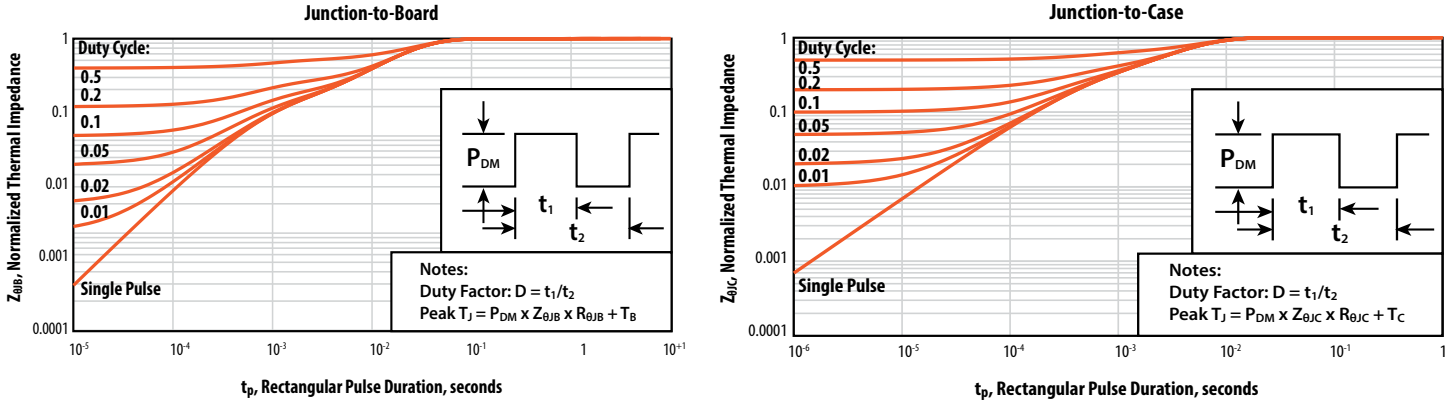
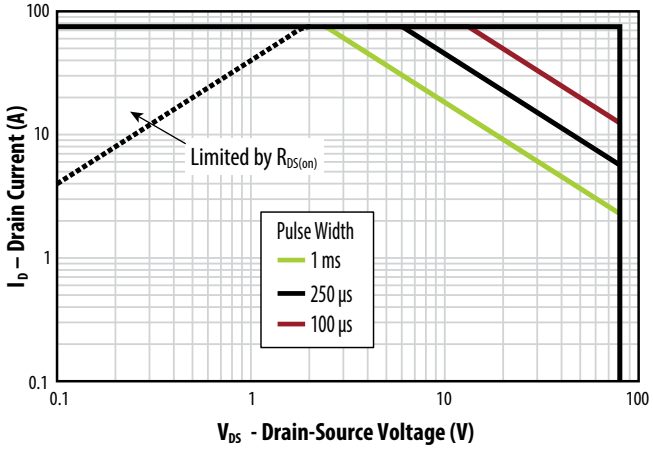
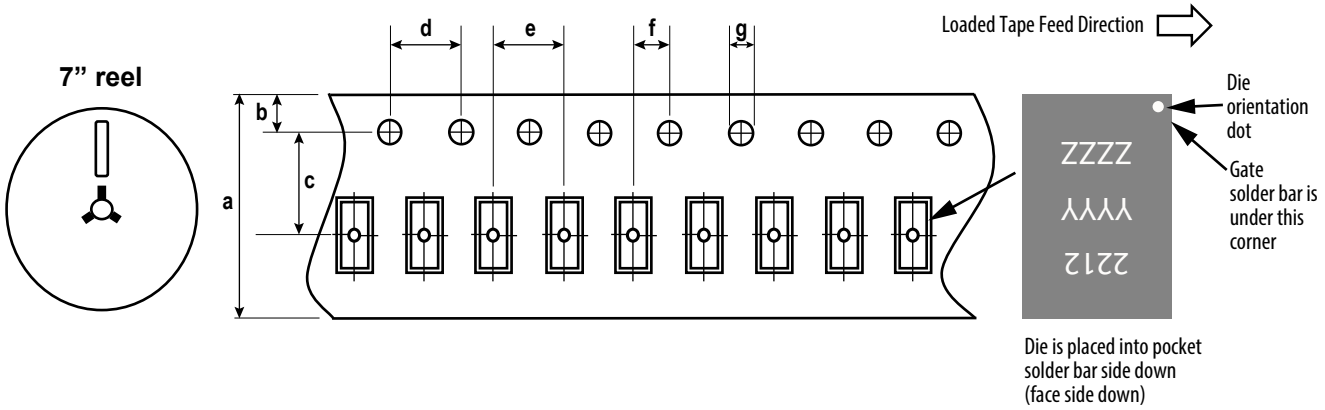


Figure 12: Safe Operating Area



TAPE AND REEL CONFIGURATION

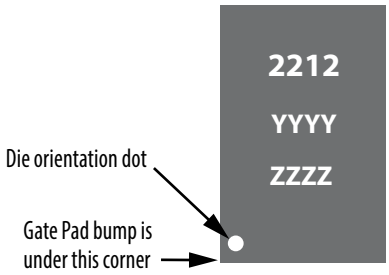
4mm pitch, 8mm wide tape on 7" reel



	EPC2212 (note 1)		
Dimension (mm)	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

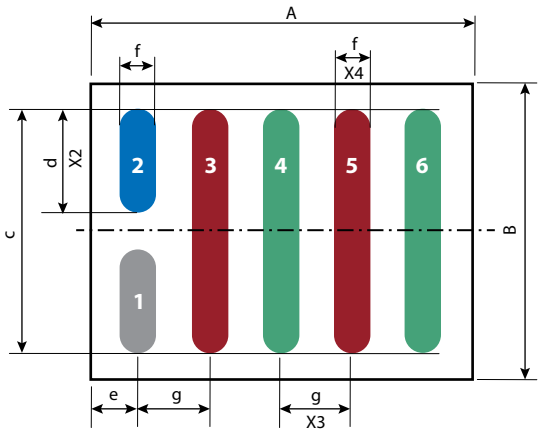
DIE MARKINGS



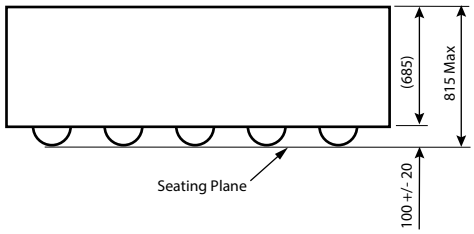
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC2212	2212	YYYY	ZZZZ

DIE OUTLINE

Solder Bar View



Side View



DIM	MICROMETERS		
	MIN	Nominal	MAX
A	2076	2106	2136
B	1602	1632	1662
c	1379	1382	1385
d	577	580	583
e	235	250	265
f	195	200	205
g	400	400	400

Pad no. 1 is Gate;

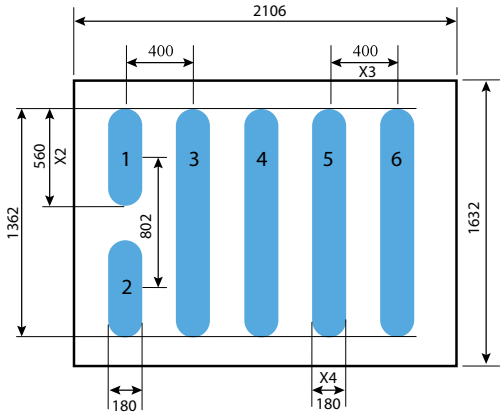
Pads no. 3, 5 are Drain;

Pads no. 4, 6 are Source;

Pad no. 2 is Substrate.

RECOMMENDED LAND PATTERN

(units in µm)



The land pattern is solder mask defined.

Pad no. 1 is Gate;

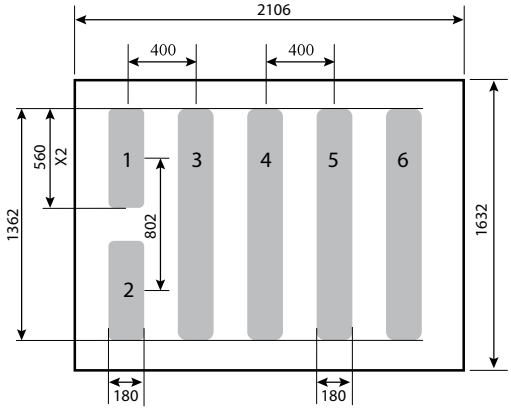
Pads no. 3, 5 are Drain;

Pads no. 4, 6 are Source;

Pad no. 2 is Substrate.

RECOMMENDED STENCIL DRAWING

(measurements in µm)



Recommended stencil should be 4mil (100 µm) thick, must be laser cut , opening per drawing. The corner has a radius of R60

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx